Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r	
10/810,229	JEDDELOH, JOSEPH	LOH, JOSEPH M.	
Examiner	Art Unit	_	
Gopal C. Ray	2111		

SEARCHED					
Class	Subclass	Date	Examiner		
710	100,300,1 04,311,5,3 03,2,305	3/29/2006	GCR		
710	316	3/29/2006	GCR		
712	11,15,34	3/29/2006	GCR		
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<b>711</b>	5,149	3/29/2006	GCR		
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709	201,219	3/29/2006	GCR		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	3/29/2006	GCR			
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	3/28/2006	GCR			
EAST: USPT (see search history printouts)	3/28/2006	GCR			
NPL: IEEE Xplore (see search history printouts)	3/28/2006	GCR			